Specifications

Drawing No.	USY1M-H1-16575-00	1 /10
Issued Date.	Jun,3,2016	

Messrs: Digi-Key

Note: Part Number will be revised in case of specification change.

Product Type	Quartz Crystal	
Series	CX2016DB	
Frequency	48000kHz	
Customer Part Number	-	
Customer Specification Number	-	
KYOCERA Part Number	CX2016DB48000E0DLFA1	
Remarks Pb-Free, RoHS Compliant, MSL 1		

Customer Approval

Approval Signature	Approved Date	
	Department	
	Person in charge	

Seller

KYOCERA Crystal Device Corporation (Sales Division) 6 Takeda Tobadono-cho, Fushimi-ku, Kyoto 612-8501 Japan TEL. No. 075-604-3500 FAX. No. 075-604-3501

Manufacturer

KYOCERA Crystal Device Corporation Crystal Units Division 5850, Higashine-Koh, Higashine-Shi, Yamagata 999-3701 Japan TEL. No. 0237-43-5611 FAX. No. 0237-43-5615

Design Department	Quality Assurance	Approved by	Checked by	Issued by
KYOCERA Crystal Device Corporation Crystal Unit Design Engineering Section Crystal Units Division	S.Itoh	T.Soda	A.Muraoka	Y.Nozaki

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Revision History

Rev.No.	Description of revise	Date	Approved by	Checked by	Issued by
00	First Edition	Jun,3,2016	T.Soda	A.Muraoka	Y.Nozaki

1. APPLICATION

The purpose of this document is applied to CX2016DB quartz crystal.

2. KYOCERA PART NUMBER

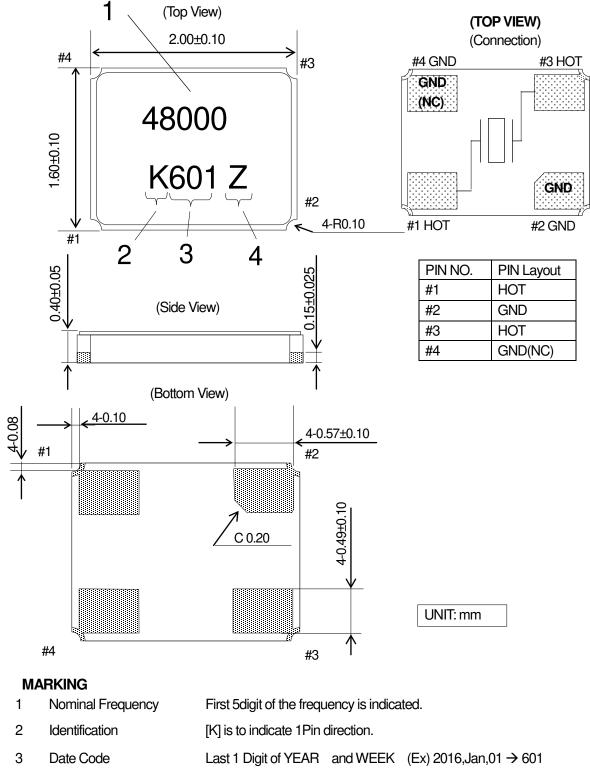
CX2016DB48000E0DLFA1

3. RATINGS

Items	SYMB.	Rating	Unit	Remarks
Operating Temperature range	Topr	-30~+85	deg. C	
Storage Temperature range	Tstg	-40~+85	deg. C	

4. CHARACTERISTICS 4-1 ELECTRICAL CHARACTERISTICS

Items		Electrical Specification				Test Condition	Remarks
	SYMB.	Min	Тур.	Max	Unit		Tiemaiks
Mode of Vibration		F	undame	ntal			
Nominal Frequency	F0		48		MHz		
Nominal Temperature	T _{NOM}		+25		°C		
Load Capacitance	CL		11.1		pF	IEC 60444-8 STD (Pi circuit 41901A)	
Frequency Tolerance	df/F	-8.0		+8.0		Network Analyzer E5100A	
Frequency Temperature characteristics	df/F	-10.0		+10.0	PPM	-30~+85°C	
Frequency Ageing Rate		-2.0		+2.0		5 years	At +25±3°C
Equivalent Series Resistance	ESR			22	Ω		
Spurious mode series resistance		1100			Ω		±700kHz
Drive Level	Pd	10		100	μW		
Insulation Resistance	IR	500			MΩ	100V(DC)	
Shunt Capacitance	C ₀	0.64	0.84	1.04	pF	IEC 60444-8 STD (Pi circuit 41901A)	
Motional Capacitance	C ₁	2.16	3.16	4.16	fF		
Motional Inductance	L ₁	1.00	3.49	4.00	mH		

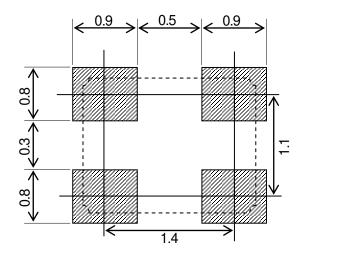


5. APPEARANCES, PHYSICAL DIMENSION OUTLINE DIMENSION (not to scale)

- 4 Manufacturing Location Y→Japan (Yamagata)
 - Z→Japan (Shiga Yohkaichi) T→Thailand

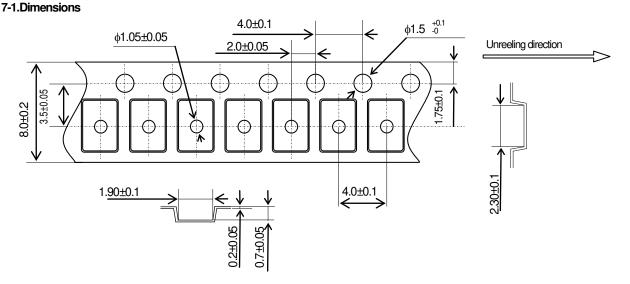
*The font of marking is for reference only.

6. RECOMMENDED LAND PATTERN (not to scale)

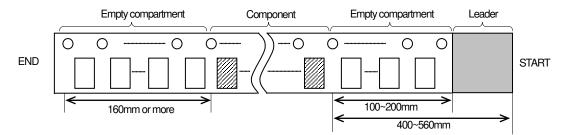




7. TAPING & REEL



7-2.Leader and Carrier tape



7-3.Direction (Orientation shall be checked from the top cover tape side)

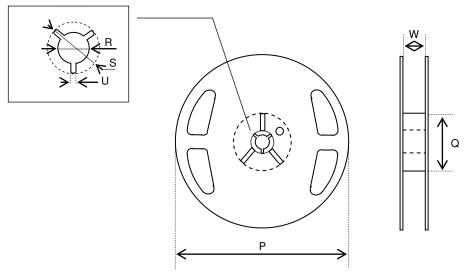


7-4.Specification

- 1. Material of the carrier tape is either polystyrene or A-PET (ESD).
- 2. Material of the cover tape is polyester (ESD).
- 3. The seal tape shall not cover the sprocket holes and not protrude from the carrier tape.
- 4. Tensile strength of carrier tape: 10N or more.
- 5. The R of the corner of each cavity is 0.2RMAX.
- 6. The alignment between centers of the cavity and sprocket hole shall be 0.05mm or less.
- 7. The orientation shall be checked from the top cover tape side as shown in 7-3.
- 8. Peeling force of cover tape: 0.1 to 1.0N.
- 9. The component will fall out naturally when cover tape is removed and set upside down.

Cover tape 165°~180° Carrier tape E

7-5.Reel Specification



Symbol	Р	Q	R
Dimension	φ180 +0/-3	φ 60 +1/- 0	φ13±0.2
Symbol	S	U	W
Dimension	φ21±0.8	2.0±0.5	9±1

(Unit: mm)

6330 Reel (15,000 pcs Max.)

Symbol	Р	Q	R
Dimension	φ330±2.0	φ100±1.0	φ13±0.2
Symbol	S	U	W
Dimension	φ21±0.8	2.0±0.5	9.4±1.0

(Unit: mm)

8. Environmental requirements

After conducting the following tests, component needs to meet below conditions. Frequency: Fluctuation within +/-10 x 10^{-6} CI: Fluctuation within +/-20% or 5 Ω whichever is larger

8.1	Resistance to Shock	Test condition 3 times natural drop from 100cm onto hard wooden board.		
8.2	Resistance to Vibration	Test conditionfrequency: 10 - 55 - 10 HzAmplitude: 1.5mmCycle time: 15 minutesDirection: X,Y,Z (3direction),2h each.		
8.3	Resistance to Heat	Test condition The quartz crystal unit shall be stored at a temperature of +85±2°C for 500h and subjected to room temperature for 1h before measurement.		
8.4	Resistance to Cold	Test condition The quartz crystal unit shall be stored at a temperature of -40±2°C for 500h and subjected to room temperature for 1h before measurement.		
8.5	Thermal Shock	Test conditionThe quartz crystal unit shall be subjected to 500 temperature cycles shown in table below, Then it shall be subjected to room temperature for 1h before mesurement.Cycle:-40±2°C (30min.) \rightarrow +25±2°C(5min.) \rightarrow +85±2°C(30min.) \rightarrow +25±2°C(5min.)		

8.6	Resistance to Moisture	Test condition
		The quartz crystal unit shall be stored at a
		temperature of +60±2°C with relative humidity of
		90% to 95% for 240 h. Then it shall be subjected
		to room temperature for 1h before measurement.

8.7 Soldering condition 1.) Type of solder

Material \rightarrow lead free solder paste Melting point \rightarrow +220±5°C

2.) Reflow temp.profile

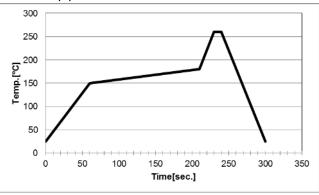
	Temp [°C]	Time[sec]		
Preheating	+150 to +180	150 (typ.)		
Peak	+260±5	10 (max.)		
Total	-	300 (max.)		

Frequency shift : ±2ppm

3.) Hand Soldering +350°C 3 sec max

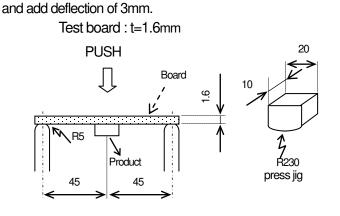
4.) Reflow Times 2 times in below Reflow temp. profile

Reflow temp.profile



8.8 Bending Strength

Solder this product in center of the circuit board (40mm X 100mm),



UNIT: mm

9. Cautions for use

(1) Soldering upon mounting

There is a possibility to influence product characteristics when Solder paste or conductive glue comes in contact with product lid or surface.

(2) When using mounting machine

Please minimize the shock when using mounting machine to avoid any excess stress to the product.

(3) Conformity of a circuit

We strongly recommend to make sure that Negative resistance (Gain) of IC is designed to be 3 times the ESR (Equivalent Series Resistance) of crystal unit.

10. Storage conditions

Please store product in below conditions, and use within 6 months. Temperature +18 to +30°C, and Humidity of 20 to 70 % in the packaging condition.

11. Manufacturing location

Kyocera Crystal Device Corporation Yamagata Plant Kyocera Crystal Device Corporation Shiga Yohkaichi Plant Kyocera Crystal Device (Thailand) Co., Ltd

12. Quality Assurance

To be guaranteed by Kyocera Crystal Device Quality Assurance Division

13. Quality guarantee

In case when Kyocera Crystal Device Corporation rooted failure occurred within 1year after its delivery, substitute product will be arranged based on discussion. Quality guarantee of product after 1year of its delivery is waivered.

14. Others

In case of any questions or opinions regarding the Specification, please have it in written manner within 45 days after issued date.